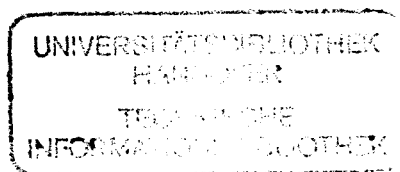
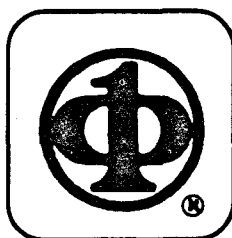


# ETC91

**2nd European Test Conference  
Munich, April 10-12, 1991**

## **PROCEEDINGS**



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89



# Table of contents

## Session 1: "1149.1 Compatible Test Chips"

Chair: *K. Parker*, Hewlett-Packard, USA

Co-ordinator: *C. Maunder*, BTRL, UK

**Paper 1.1: The Boundary-Scan Master: Architecture and Implementation** . . . . . 1

*N. Jarwala, C. W. Yau*

AT & T Bell Labs. USA

**Paper 1.2: Self-Test of a 256 k × 4 bit Stand-Alone Static RAM** . . . . . 11

*R. H. A. Rijk, R. W. C. Dekker, H. G. Kerkhoff*

University of Twente, The Netherlands

**Paper 1.3: Boundary Scan and BIST Compatible IEEE 1149.1: VHDL & Autosynthesis Design of a SRAM Tester Macrocell and Chip** . . . . . 17

*S. Kritter, E. Mackowiak*

SGS-Thomson Microelectronics, France

## Session 2: "Stimuli Generation and Signature Analysis in BIST Structures"

Chair: *T. W. Williams*, IBM, USA

Co-ordinator: *E. Aas*, Trondheim University, Norway

**Paper 2.1: LFSR based Deterministic and Pseudo-Random Test Pattern Generator Structures** . . . . . 27

*C. Dufaza, G. Cambon*

LAMM, France

**Paper 2.2: IC Realization of a Cellular Automata Based Self-Test Strategy for Programmable Data Paths** . . . . . 35

*J. van Sas, F. Catthoor, S. Vernalde*

IMEC Laboratory, Belgium

**Paper 2.3: Experimental Analysis of Fault Coverage in Systems with Signature Registers** . . . . . 45

*J. Rajski, J. Tyszer*

McGill University, Canada

## Session 3: "BIST of Regular Structures"

Chair: *V. Yarmolik*, Minsk Radio Eng. Institute, USSR

Co-ordinator: *J.-L. Becu*, SGS-Thomson Microelectronics, France

**Paper 3.1: A Universal Test Algorithm for the Self-Test of Parametrizable Random Access Memories** . . . . . 53

*H. C. Ritter, Th. M. Schwair*

Siemens, Germany

**Paper 3.2: Test Pattern Generators for Arithmetic and Logic Units** . . . . . 61

*M. Nicolaidis*

IMAG/TIM3, France

**Paper 3.3: Parallel Self-Test and the Synthesis of Control Units** . . . . . 73

*B. Eschermann, H.-J. Wunderlich*

Karlsruhe University, Germany

## Session 4: "Advances in IC Defects-Based Testability"

Chair: *C. Hawkins*, University of New Mexico, USA

Co-ordinator: *C. Landraut*, LAMM, France

**Paper 4.1: Defect and Design Error Diagnosability Measure** . . . . . 83

*W. Maly, S. Naik*

Carnegie Mellon University, USA

**Paper 4.2: Quantifying Non-Target Defect Detection by Target Fault Test Sets** ..... 91  
*K. M. Butler, M. R. Mercer*  
Texas University, USA

**Paper 4.3: Layout-Driven Testability Enhancement** ..... 101  
*J. P. Teixeira, F. M. Concalves, J. J. T. Sousa*  
INESC, Portugal

**Session 5: "Board and System Fault Location"**

Chair: *M. Mezzalama*, Politecnico di Torino, Italy  
Co-ordinator: *D. Laurent*, Bull Systems, France

**Paper 5.1: Test Data Collecting System: A Paperless Test, Troubleshoot and Repair** ... 111  
*L. Daemen*  
Alcatel Bell, Belgium

**Paper 5.2: Troubleshooting Digital Circuit Boards by Means of an Expert System: An Approach at Alcatel Bell** ..... 123  
*J. Vanwelkenhuysen*  
Vrije University, Belgium

**Paper 5.3: Distributed Diagnosis of Faults in a Multiple-Path Multi-Stage Interconnection Network** ..... 133  
*S-J. Wang*  
Princeton University, USA

**Session 6: "Advances in CMOS/BICMOS Testing"**

Chair: *W. Maly*, Carnegie-Mellon University, USA  
Co-ordinator: *C. Lopez-Barrio*, Telefonica I + D, Spain

**Paper 6.1: Fault Modelling of Gate Oxide Shorts Gloating Gate and Bridging Failures in CMOS Circuits** ..... 143  
*V. H. Champac, R. Rodriguez-Montanés, J. A. Segura, J. Figueras, J. A. Rubio*  
UPC, Spain

**Paper 6.2: Comparing Stuck Fault and Current Testing via CMOS Chip Test** ..... 149  
*T. Storey, W. Maly, J. Andrews, M. Miske*  
Carnegie Mellon University, National Semiconductor, USA

**Paper 6.3: Failure Mechanisms in BiCMOS Sea-of-Gate Arrays** ..... 157  
*W. Denner, G. Tröster, A. Wedel, E. Zocher*  
Telefunken, Germany

**Session 7: "High-Performance Fault Simulation"**

Chair: *M. Kessler*, IBM Deutschland, Germany  
Co-ordinator: *M. Melgara*, CSELT, Italy

**Paper 7.1: Vector Length Control for Compiled Code Event Driven Pattern Parallel Fault Simulation** ..... 165  
*W. Daehn, D. Kannemacher, J. Castagne*  
Hannover University, Germany

**Paper 7.2: An Efficient Parallel Pattern Gate Delay Fault Simulator with Accelerated Detected Fault Size Determination Capabilities** ..... 171  
*F. Fink, K. Fuchs, M. H. Schulz*  
TU Munich, Siemens, Germany

**Paper 7.3: Switch-Level Fault Simulation by Critical Path Tracing** ..... 181  
*M. Dalpasso, M. Favalli, P. Olivo, B. Ricco*  
Bologna University, Italy

**Session 8: "Standards for Test-Information Interchange"**

Chair: *H. Wojtkowiak*, University of Siegen, Germany

Co-ordinator: *M. Wahl*, University of Siegen, Germany

**Paper 8.1: A User's Introduction to WAVES** ..... 191

*R. Hillman, F. Koo, L. Shombert*

RADC, Hughes Aircraft, Harris Corporation, USA

**Paper 8.2: EDIF as a Standard Test Specification Format** ..... 201

*P. Vandelo*

IMEC, Belgium

**Paper 8.3: An Automatic Test Program Generation Strategy Using a Tester-Independent Waveform Representation** ..... 209

*Louis Testa, R. Lunde*

TSSI, Beaverton, USA

**Session 9: "Fault Simulation and ATPG"**

Chair: *C. Almeida*, INESC, Portugal

Co-ordinator: *M. Schulz*, Siemens-Nixdorf, Germany

**Paper 9.1: Testing Finite State Machines Implemented by Programmable Logic Devices** ..... 217

*F. Corsi, S. Martino, A. L. Sangiovanni-Vincentelli*

Bari University, Italy; Berkeley University, USA

**Paper 9.2: Distributed Fault Simulation with Vector Set Partitioning** ..... 227

*A. Warshawsky, J. Rajski*

McGill University, Canada

**Paper 9.3: LFSR-Coded Test Patterns for Scan Designs** ..... 237

*B. Koenemann*

IBM, USA

**Session 10: "Scan Optimisation Techniques"**

Chair: *J. Jamieson*, Alcatel, Belgium

Co-ordinator: *F. Beenker*, Philips Research, The Netherlands

**Paper 10.1: A Model for Test-Time Reduction of Scan Testable Circuits** ..... 243

*S. Oosdikj, F. Beenker, L. Thijssen*

Philips Research Labs, Delft University, The Netherlands

**Paper 10.2: Test Point Insertion for Scan-Based BIST** ..... 253

*B. H. Seiss, P. M. Trouborst, M. H. Schulz*

TU Munich, Germany; Bell-Northern Research, Canada; Siemens, Germany

**Paper 10.3: A Methodology for Partial Scan Design** ..... 263

*D. Pradhan, S. Nori, J. Swaminathan*

Massachusetts University, Amdahl Corp., USA

**Session 11: "Advanced ATPG"**

Chair: *G. Saucier*, INPG/CSI, France

Co-ordinator: *E. Trischler*, Siemens-Nixdorf, Germany

**Paper 11.1: Mixed Level Automatic Test Pattern Generation for CMOS Circuits** ..... 273

*M. L. Flottes, C. Landrault, S. Paul, S. Pravossoudovitch*

LAMM, France

**Paper 11.2: MINOTAUR — A Mixed Level Test Pattern Generator for VLSI Circuits** ..... 283

*J. M. C. Geada, G. Russell*

Newcastle upon Tyne University, UK

**Paper 11.3: Advanced Techniques for Sequential Test Generation** ..... 293

*N. Gouders, R. Kaibel*

Duisburg University, Germany

**Session 12: "Analogue and Mixed-Signal Testing"**  
Chair: *K. Baker*, Philips Research Labs., The Netherlands  
Co-ordinator: *J.-P. Teixeira*, INESC, Portugal

**Paper 12.1: A Novel Technique for Testing Mixed-Signal I. C.'s** ..... 301  
*P. S. Evans, M. A. Al-Qutayri, P. R. Shepherd*  
Bath University, UK

**Paper 12.2: Hybrid Built-In Self-Test (HBIST) for Mixed Analogue/Digital Integrated Circuits** ..... 307  
*M. J. Ohletz*  
Hannover University, Germany

**Paper 12.3: Automatic Test of T1 and CEPT Line Interface Units** ..... 317  
*D. J. Derian*  
LTX, USA

**Session 13: "Testable Design through Testability Analysis"**  
Chair: *J. Soden*, Sandia Labs., USA  
Co-ordinator: *P. Prinetto*, Politecnico di Torino, Italy

**Paper 13.1: Hierarchical Functional Level Testability Analysis** ..... 327  
*B. H. Naim, B. Kaminska*  
Montreal Polytechnic, Canada

**Paper 13.2: On Bridging Fault Controllability and Observability and Their Correlations to Detectability** ..... 333  
*R. Kapur, K. M. Butler, M. R. Mercer*  
Texas University, USA

**Paper 13.3: Trade-off Analysis of the Effectiveness of Testability Estimators** ..... 341  
*R. Kapur, J. Ferguson, M. Abadir*  
Texas University, USA

**Session 14: "High-Performance Fixturing in IC Testing"**  
Chair: *A. Wakeling*, Schlumberger, UK  
Co-ordinator: *F. Pool*, Philips Components, The Netherlands

**Paper 14.1: Impedance Matching Circuit for Dynamic Correction of Device/ATE Impedance Mismatch** ..... 351  
*M. C. Kohalmy*  
Teradyne, USA

**Paper 14.2: High Speed Fixturing of Chips and Wafers for Electron Beam Probing** .. 361  
*K. Helmreich, M. Chowanetz*  
Erlangen-Nürnberg University, Germany

**Paper 14.3: Groundbounce in ASIC's: Modelling and Test Results** ..... 367  
*L. Diaz-Olavarrieta*  
Bell, Canada

**Session 15: "Boundary Scan in Practice"**  
Chair: *R. Tulloss*, AT & T Bell Labs., USA  
Co-ordinator: *C. Maunder*, BTRL, UK

**Paper 15.1: A Test Economics Model & Cost-Benefit Analysis of Boundary Scan** ... 375  
*J. Miles, R. De Bondt, L. Daemen*  
Alcatel Bell, Belgium

**Paper 15.2: Built-In Pad Test with Boundary Scan** ..... 385  
*T. Schwederski, T. Büchner, J. Leenstra, G. Roos, L. Spaanenburg*  
Institute for Microelectronics Stuttgart, Germany

**Paper 15.3: Assessing Fault Coverage in Virtual Incircuit Testing of Partial Boundary-Scan** ..... 393  
*P. Hansen*  
Teradyne USA

**Session 16: "Test Pattern Preparation"**

Chair: *M. Gerner*, Siemens, Germany  
Co-ordinator: *W. Daehn*, Sican, Germany

**Paper 16.1: Intent Documentation in a Graphical Test Programme Editor Simplifies the Logic Simulator — Tester Link** ..... 397  
*R. W. Werthebach*  
Braunschweig University, Germany

**Paper 16.2: Device-Oriented Test Program Generation using the Sequencer-Per-Pin Test System Architecture** ..... 405  
*C. Tinaztepe, P. David*  
Schlumberger USA; Schlumberger France

**Paper 16.3: High Level Representation of ATE Patterns** ..... 413  
*A. R. Taylor*  
LTX/Trillium, USA

**Session 17: "Macrotest Tools and Techniques"**

Chair: *G. Robinson*, GenRad, USA  
Co-ordinator: *B. Courtois*, IMAG/TIM3, France

**Paper 17.1: Interactive Test Strategy planning: Model and a Prototype** ..... 417  
*M. Laffitte*  
Siemens, Germany

**Paper 17.2: Minimization of Test Control Blocks** ..... 427  
*E. J. Marinissen, R. Dekker*  
Philips Research Labs, The Netherlands

**Paper 17.3: An Economics Based Test Strategy Planner for VLSI Design** ..... 437  
*C. Dislis, J. Dick, A. P. Ambler*  
Brunel University, UK

**Paper 17.4: Automatic Test-Specification Generation for Macro-Level BIST Based on the Boundary-Scan Standard** ..... 447  
*R. P. van Riessen, H. G. Kerkhoff*  
University of Twente, The Netherlands

**Session 18: "Test System Architectures and Performance"**

Chair: *C. da Costa*, Teradyne, Germany  
Co-ordinator: *F. Pool*, Philips Components, The Netherlands

**Paper 18.1: Performance Characteristics of a IGbps Digital Test System** ..... 455  
*D. C. Keezer*  
South Florida University, USA

**Paper 18.2: Implementing Per-Pin Architecture VLSI for WLR EM parametric testing** . 463  
*E. Weis, E. Kinsbron, A. Cohen, G. Chanoch, B. Vogel, N. Croitoru*  
Tel Aviv University, Israel

**Paper 18.3: Remote Communications on the Tester Workstation** ..... 467  
*D. Dowding*  
LTX/Trillium, USA

**Paper 18.4: Graphic Displays for Non-Graphic Test Data** ..... 473  
*A. E. Downey*  
Ando Corporation, USA

## Posters

<b>Poster: Production Method Using IEEE 1149.1 Today</b> .....	479
<i>Jan-Erik Rieckgard, Schlumberger ATE, Sweden</i>	
<b>Poster: Intelligent Probe Sample Placement</b> .....	480
<i>C. G. McKay, Schlumberger Technologies, UK</i>	
<b>Poster: Integrating Design for Test Through Concurrent Engineering — Practical Implementations</b> .....	481
<i>Jon Turino, Logical Solutions Technology, Inc., USA</i>	
<b>Poster: On the Selection of a Partial Scan Path with Respect to Target Faults</b> .....	482
<i>Harald Gundlach, University Erlangen-Nürnberg, Germany</i>	
<b>Poster: The Design and Implementation of an Efficient Method to Generate Protocol Conformance Test Sequence</b> .....	483
<i>Johnny S. K. Wong, Iowa State University, USA</i>	
<b>Poster: CMOS Test Generation for High Fault Coverage by Switch Level to Gate Level Coupling</b> ...	484
<i>H. T. Vierhaus, GMD, Germany</i>	
<b>Poster: Pseudoexhaustive Test Sets Generated in LFSRs</b> .....	485
<i>Ondřej Novák, Technical Univ. of Liberec, Czechoslovakia</i>	
<b>Poster: A Fast Parallel Pattern Fault Simulator for Combinational Circuits</b> .....	486
<i>Dong S. Ha, Virginia Polytechnic Institute and State University, USA</i>	
<b>Poster: Test Generation for Digital Systems at Functional Level</b> .....	487
<i>Krzysztof Kuchcinski, Linköping University, Sweden</i>	
<b>Poster: On Parallel Test Pattern Generation Algorithms</b> .....	488
<i>Tapan J. Chakraborty, AT &amp; T Bell Laboratories, USA</i>	
<b>Poster: Logical Layer Conformance Testing of Parallel Bus Interfaces</b> .....	489
<i>Bernhard Müller, Forschungszentrum Informatik, Germany</i>	
<b>Poster: Modular Testing of a VLSI Processor Chip Using the BED System</b> .....	490
<i>Bernd Hanstein, Siemens, Germany</i>	
<b>Poster: An E-Beam Prober Based VLSI Device Characterization System</b> .....	491
<i>Peter Cundall, Schlumberger Technologies, USA</i>	
<b>Poster: An E-Beam Prober Based VLSI Device Characterization System</b> .....	491
<i>Peter Cundall, Schlumberger Technologies, USA</i>	
<b>Poster: VLSI Logic Verification Program Generator</b> .....	492
<i>Ajit Dingankar, Tien N. Le, IBM Corporation, USA</i>	
<b>Poster: Towards Functional Testing From a VHDL Data Flow Description</b> .....	493
<i>P. Wodey, Lab. de Genie Informatique, France</i>	
<b>Poster: Simplified Test Strategies for Analogue Integrated Circuits</b> .....	494
<i>A. P. Dorey, University of Lancaster, UK</i>	
<b>Poster: E-Beam Testing For Microprocessor Failure Location</b> .....	495
<i>J. Cabestany, UPC, Spain</i>	
<b>Poster: Improved Probing in Analogue Diagnosis</b> .....	496
<i>Antony Wakeling, Schlumberger Technologies, UK</i>	
<b>Poster: Design &amp; Test Integration</b> .....	497
<i>Ruedi H. Egger, GenRad, Switzerland</i>	

<b>Poster:</b>	<b>Integral Test Strategy for Telecommunications Line-Cards</b> .....	498
	<i>Dirk van de Lagemaat, Philips Communication Systems, The Netherlands</i>	
<b>Poster:</b>	<b>A Hierarchical Test Generator for CMOS Bridging Faults</b> .....	499
	<i>Will R. Moore, University of Oxford, UK</i>	
<b>Poster:</b>	<b>Functional Model and Self-Testing in VHDL for Functional Test Generation</b> .....	500
	<i>Heinz-Dieter Hümmer, University of Duisburg, Germany</i>	
<b>Poster:</b>	<b>PATSIM: An Automatic Test Pattern Generator in DISIM</b> .....	501
	<i>Harbhajan Singh, Daimler-Benz, Germany</i>	
<b>Poster:</b>	<b>A New Algorithm for Diagnosing Interconnect Faults on Boundary Scan Boards</b> .....	502
	<i>José Manuel M. Ferreira, INESC, Portugal</i>	
<b>Poster:</b>	<b>A New Prototype for ASIC Functional Testing</b> .....	503
	<i>Carlos Beltán, INESC, Portugal</i>	
<b>Poster:</b>	<b>A New Path Delay Fault Simulation Algorithm</b> .....	504
	<i>Yuejian Wu, University of British Columbia, Canada</i>	
<b>Poster:</b>	<b>Algorithms for VLSI Error Location Applied to an E-Beam Validation System</b> .....	505
	<i>P. Garino, CSELT, Italy</i>	
<b>Poster:</b>	<b>Timing Oriented Testing for VLSIs</b> .....	506
	<i>Frank Dymann, Siemens, Germany</i>	
<b>Poster:</b>	<b>Probability Driven Partial Scan Design</b> .....	507
	<i>Chung Len Lee, National Chiao Tung University, Taiwan, R.O.C.</i>	
<b>Poster:</b>	<b>Digital Simulators in Test; Conversion of Waveforms to Test Language</b> .....	508
	<i>Gordon F. Taylor, GenRad, USA</i>	
<b>Poster:</b>	<b>Using Emulation Techniques In General Purpose ATE</b> .....	509
	<i>R. Wade Williams, GenRad, USA</i>	
<b>Poster:</b>	<b>Phoebus: A Tool for Hierarchical Testability and Redundancy Analysis</b> .....	510
	<i>Jean-Claude Geffroy, INSAT/DGE/GERII, France</i>	
<b>Poster:</b>	<b>Boundary Scan Design for a Memory Controller</b> .....	511
	<i>Peter L. Harrod, Advanced RISC Machines Ltd., UK</i>	
<b>Poster:</b>	<b>Developments for Built-in-Self-Test of Mixed ASICs</b> .....	512
	<i>Rosemary A. Cobley, Exeter University, UK</i>	
<b>Poster:</b>	<b>Implementing Boundary-Scan and Pseudo-Random Built-in Self Test in a 0.7 Micron CMOS Asynchronous Transfer Mode Switch</b> .....	513
	<i>P. Thorel, C.N.E.T., France</i>	
<b>Poster:</b>	<b>Parsimonious Test Concept for Embedded PLAs in Boundary Scan Environment</b> .....	514
	<i>Einar J. Aas, Norwegian Inst. of Technology, Norway</i>	
<b>Poster:</b>	<b>Towards Automated Diagnostic: E-Beam Tester Data Base Environment</b> .....	515
	<i>Laurence Primot, IBM, France</i>	
<b>Poster:</b>	<b>Tradeoffs in Self-Test and External Test of PLAs</b> .....	516
	<i>Einar J. Aas, Norwegian Inst. of Technology, Norway</i>	
<b>Poster:</b>	<b>Simulation for Delay Faults</b> .....	517
	<i>Y. Xing, University of Twente, The Netherlands</i>	
<b>Poster:</b>	<b>Hierarchical Approach to Test Pattern Generation</b> .....	518
	<i>E. C. Weening, University of Twente, The Netherlands</i>	
<b>Poster:</b>	<b>Autonomously Testable Dynamic CMOS PLAs</b> .....	519
	<i>M. Renovell, LAMM, France</i>	
<b>Poster:</b>	<b>A High-Level Pattern Development System Promoting Industrial Concurrent Engineering</b> .....	520
	<i>Gunter T. Krampf, Siemens, Austria</i>	



<b>Poster:</b>	<b>Automatic Test Pattern and Test Program Generation for VLSI Scan Designs</b> .....	521
	<i>Friedrich Hapke, Philips Components, Germany</i>	
<b>Poster:</b>	<b>Test of Analog Components in a Digital Environment</b> .....	522
	<i>Martin Viktil, EB Technology, Norway</i>	
<b>Poster:</b>	<b>Self-Checking Circuits in Presence of Bridging Faults. Possibilities of Current Sensing in XOR Parity Trees</b> .....	523
	<i>Luz Balado, UPC, Spain</i>	
<b>Poster:</b>	<b>Design for Contactless Testability in a Scan-Path Environment</b> .....	524
	<i>Josef Gross, Universität Hannover, Germany</i>	
<b>Poster:</b>	<b>Spectrum Analysis of Small-Bandwidth Signals Using a Modulated Electron Beam</b> .....	525
	<i>W. Kern, SEL Alcatel, Germany</i>	
<b>Poster:</b>	<b>Looking for Functional Fault Equivalence</b> .....	526
	<i>Antonio Lioy, Politecnico di Torino, Italy</i>	
<b>Poster:</b>	<b>An Application of Automata Theory to sequential ATPG</b> .....	527
	<i>Paolo Prinetto, Politecnico di Torino, Italy</i>	
<b>Poster:</b>	<b>Test Generation by Fault Sampling: Estimates of Population Coverage</b> .....	528
	<i>Hassan Farhat, University of Nebraska, USA</i>	
<b>Poster:</b>	<b>The Challenge of Designing a Tester that is Compatible and Different at the Same Time</b> .....	529
	<i>John Doyle, GenRad, UK</i>	
<b>Poster:</b>	<b>Implementing a Parallel/Serial Converter for Board Scan Test</b> .....	530
	<i>Jay Brown, National Semiconductor, USA</i>	
<b>Poster:</b>	<b>A Proposal for Extending the IEEE Standard 1149.1 Test Access Port to System Backplanes</b> .....	531
	<i>Dilip Bhavasar, Digital Equipment, USA</i>	
<b>Poster:</b>	<b>A Reduced Lost Fault Simulation Strategy for the AM29050 TM Microprocessor</b> .....	532
	<i>Gopi Ganapathy, Advanced Micro Devices, USA</i>	